

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/791,602 WALDSPURGER ET AL.	
		Examiner	Art Unit	Page 1 of 3 JAMES TURCHEN 2439

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,414,833 A	05-1995	Hershey et al.	726/22
*	B	US-5,440,723 A	08-1995	Arnold et al.	714/2
*	C	US-5,696,822 A	12-1997	Nachenberg, Carey	726/24
*	D	US-5,826,013 A	10-1998	Nachenberg, Carey S.	726/22
*	E	US-5,919,257 A	07-1999	Trostle, Jonathan	726/22
*	F	US-5,964,889 A	10-1999	Nachenberg, Carey S.	714/25
*	G	US-6,021,510 A	02-2000	Nachenberg, Carey	714/38
*	H	US-6,094,731 A	07-2000	Waldin et al.	714/38
*	I	US-6,122,738 A	09-2000	Millard, John	713/187
*	J	US-6,148,401 A	11-2000	Devanbu et al.	713/170
*	K	US-6,275,938 B1	08-2001	Bond et al.	726/23
*	L	US-6,338,141 B1	01-2002	Wells, Joseph W.	726/24
*	M	US-6,357,008 B1	03-2002	Nachenberg, Carey S.	726/24

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/791,602 WALDSPURGER ET AL.	
		Examiner	Art Unit	Page 2 of 3 JAMES TURCHEN 2439

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,381,698 B1	04-2002	Devanbu et al.	713/170
*	B	US-6,397,242 B1	05-2002	Devine et al.	718/1
*	C	US-2002/0077782 A1	06-2002	Fruehling et al.	702/185
*	D	US-2003/0023863 A1	01-2003	El Fassi et al.	713/200
*	E	US-6,651,080 B1	11-2003	Liang et al.	718/1
*	F	US-6,678,825 B1	01-2004	Ellison et al.	726/17
*	G	US-6,697,810 B2	02-2004	Kumar et al.	707/10
*	H	US-6,763,466 B1	07-2004	Glover, Michael	726/24
*	I	US-6,775,780 B1	08-2004	Muttik, Igor	726/24
*	J	US-2005/0108562 A1	05-2005	Khazan et al.	713/200
*	K	US-6,981,176 B2	12-2005	Fruehling et al.	714/11
*	L	US-6,973,577 B1	12-2005	Kouznetsov, Victor	726/25
*	M	US-7,010,698 B2	03-2006	Sheymov, Victor I.	713/194

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/791,602 WALDSPURGER ET AL.	
		Examiner	Art Unit	Page 3 of 3 JAMES TURCHEN 2439

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,069,583 B2	06-2006	Yann et al.	726/4
*	B	US-7,082,615 B1	07-2006	Ellison et al.	726/26
*	C	US-7,093,239 B1	08-2006	van der Made, Peter A. J	717/135
*	D	US-7,093,135 B1	08-2006	Radatti et al.	713/188
*	E	US-7,117,488 B1	10-2006	Franz et al.	717/144
*	F	US-7,146,305 B2	12-2006	van der Made, Peter A. J.	703/22
*	G	US-7,188,367 B1	03-2007	Edwards et al.	726/24
*	H	US-7,367,057 B2	04-2008	Das et al.	726/24
*	I	US-7,631,356 B2	12-2009	Hatlelid et al.	726/24
J	US-				
K	US-				
L	US-				
M	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.